

Brumley South Surplus Requirements Date2-12-08

Metrology

<u>Manufacturer</u>	<u>Model Number</u>	<u>Application</u>	<u>Alternate Tool Designations</u>
Tencor, KLA/Tencor	Flexus 2320	Stress Measurement Tool	FLX 2320, FLX, Stress Measurement
Tencor, KLA/Tencor	Flexus 5400	Stress Measurement Tool	FLX 5400, FLX, Stress Measurement
Tencor, KLA/Tencor	Flexus 5200	Stress Measurement Tool	FLX 5200, FLX, Stress Measurement
Tencor, KLA/Tencor	Flexus 2300	Stress Measurement Tool	FLX 2300, FLX, Stress Measurement
Tencor, KLA/Tencor	Flexus 2908	Stress Measurement Tool 900C degrees	FLX 2908, FLX, Stress Measurement
Tencor, KLA/Tencor	AS 200	Bench Top Profiler	Alpha Step 200, Alpha Step, Profiler
Tencor, KLA/Tencor	AS 500	Bench Top Profiler	Alpha Step 500, Alpha Step, Profiler
Tencor, KLA/Tencor	AS-IQ	Bench Top Profiler	Alpha Step AS-IQ, Profiler
Tencor, KLA/Tencor	P 2	Bench Top Profiler	Profiler
Tencor, KLA/Tencor	P10	Bench Top Profiler	Profiler
Tencor, KLA/Tencor	P11	Bench Top Profiler	Profiler
Tencor, KLA/Tencor	P15	Bench Top Profiler	Profiler
Tencor, KLA/Tencor	P16	Bench Top Profiler	Profiler
Tencor, KLA/Tencor	RS 75	Bench Top Resistivity Tool	Prometrix, Resistivity Tool, RS
Tencor, KLA/Tencor	RS 100	Bench Top Resistivity Tool	Prometrix, Resistivity Tool, RS
Tencor, KLA/Tencor	RS 55	Bench Top Resistivity Tool	Prometrix, Resistivity Tool, RS
Tencor, KLA/Tencor	Surfscan 6420	Stand Alone Bare Wafer Defect Tool	SFS 6420, 6420, Particle Counter
Tencor, KLA/Tencor	Surfscan 6400	Stand Alone Bare Wafer Defect Tool	SFS 6400, 6400, Particle Counter
Tencor, KLA/Tencor	Surfscan 6220	Stand Alone Bare Wafer Defect Tool	SFS 6220, 6220, Particle Counter
Tencor, KLA/Tencor	Surfscan 6200	Stand Alone Bare Wafer Defect Tool	SFS 6200, 6200, Particle Counter
Tencor, KLA/Tencor	Surfscan 6100	Stand Alone Bare Wafer Defect Tool	SFS 6100, 6100, Particle Counter
Tencor, KLA/Tencor	Surfscan 7700	Patterned Wafer Defect Tool	7700, Patterned Wafer Inspection
Dryden	Dryden QIII	Airborne Particle Counter	QII, Surface Particle Counter
Climet	CI 450t	Airborne Particle Counter	Surface Particle Counter
Climet	CI 200	Airborne Particle Counter	Surface Particle Counter
Met One	ANY MODELS	Airborne Particle Counter	Surface Particle Counter
Particle Measuring Systems	LASAIR II 110	Airborne Particle Counter	Surface Particle Counter
Nanometrics	Nano 210, 4000,4150,8000,9000	Film Measurement , Film Thickness	Nano
Thermowave	ANY (IE:2600 Series)	Thin Film Measurements	

